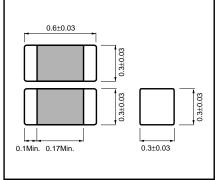
Multi-layer ceramic chip capacitors

MCH03 (0603 size, chip capacitor)

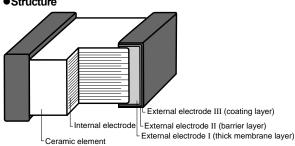
Features

- 1) Small size (0.6 x 0.3 x 0.3 mm) makes it perfect for lightweight portable devices.
- 2) Comes packed either in tape to enable automatic mounting.
- 3) Precise uniformity of shape and dimensions facilitates highly efficient automatic mounting.
- 4) Barrier layer and end terminations to improve solderability.

● External dimensions (Units : mm)



Structure



Product designation

						Code	roduct thickness	Pack	kaging specifications	Reel	Basic ordening unit (pcs.)
						K			ape (width 8 mm, pitch 2 m		
									ble with EIAJ ET-7200A	, ү ү гоогияг (г илг.)	.0,000
Part No.							iging style	compan	DIC WITH LIAG ET-1200A		
Fart No.	_					racka	iging style				
		\neg									
							=	-			
M C H 0 3 2 F N 1 0 3 Z K											
IVI C	W C H U 3 2 F N I U 3 2 K										
	- 1										
	_		_								
Rat	ted	voltage	\equiv	Capac	itance-temperature cha	aracteristics	Nominal	Capa	citance tolerance		
		voltage Voltage	Code		itance-temperature cha	aracteristics Temp. coefficient or percent change	Nominal capacitance				
	de \		Code					Code			
Cod	de \	Voltage	-	Code CG(C0G)	Operating temperature (°C)	Temp. coefficient or percent change		Code C	tolerance		
Co.	de \	Voltage 25V 16V	Α	Code CG(C0G)	Operating temperature (°C) -55~+125	Temp. coefficient or percent change 0±30ppm/°C		Code C D	tolerance ± 0.25pF (0.5 ~ 5pF)		
2 3	de \	Voltage 25V	Α	Code CG(C0G)	Operating temperature (°C) -55~+125 -55~+125	Temp. coefficient or percent change 0±30ppm/°C ±15%	capacitance	Code C D J	tolerance ± 0.25pF (0.5 ~ 5pF) ± 0.5pF (5.1 ~ 10pF) ± 5% (11pF or more)		
2 3	de \	Voltage 25V 16V	Α	Code CG(C0G) R B (X7R)	Operating temperature (°C) -55~+125 -55~+125 -25~+85	Temp. coefficient or percent change 0±30ppm/°C ±15% ±10%	capacitance 3-digit designation	Code C D	tolerance ± 0.25pF (0.5 ~ 5pF) ± 0.5pF (5.1 ~ 10pF)		
2 3	de \	Voltage 25V 16V	A CN	Code CG(C0G) R B (X7R)	Operating temperature (°C) -55~+125 -55~+125 -25~+85 (-55~+125)	Temp. coefficient or percent change 0±30ppm/°C ±15% ±10% (±15%)	capacitance 3-digit designation	Code C D J	tolerance ± 0.25pF (0.5 ~ 5pF) ± 0.5pF (5.1 ~ 10pF) ± 5% (11pF or more)		

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● Capacitance range

For thermal compensation

For thermal compensation					
Part n	Part number				
Capacitance (pF)	Temperature characteristics Rated voltage (V)	A (CG) (C0G) 25V			
	Tolerance	23 V			
0.5 0.75 1					
1.1 1.2 1.3					
1.5 1.6 1.8					
2 2.2 2.4	C (± 0.25pF)				
2.7 3 3.3					
3.6 3.9 4					
4.3 4.7 5					
5.1 5.6 6					
6.2 6.8 7	D (± 0.5pF)				
7.5 8 8.2	(= 3.56.)				
9 9.1 10					

Part n	MCH03	
Capacitance (pF)	Temperature characteristics	(CG) (C0G)
Сараспапсе (рг)	Rated voltage (V) Tolerance	25V
11		
12		
13		
15		
16		
18		
20		
22	1/ + 50/)	
24	J (± 5%)	
27		
30		
33		
36		
39		
43		
47		

Product thickness (mm) 0.3±0.03

High dielectric constant

Tilgir dioloctilo coriot				
Part n	umber	MCH03		
Capacitance (pF)	Temperature characteristics	CN (R) (B) (X7R)	FN (F) (Y5V)	
Сараспапсе (рг)	Rated voltage (V)	25V	25V	
	Tolerance	K (±10%)	Z (+80, -20%)	
100				
150				
200				
330				
470				
680				
1,000				
1,500				
2,200				
4,700				
10,000				

Product thickness (mm) 0.3±0.03

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Characteristics

Class 1 (For thermal compensation)

	Temperature characteristics					
Item		A (CG) (C0G)	Test methods/conditions (based on JIS C 5102)			
Operating temperature		−55°C ~ 125°C				
Nominal capac	itance (C)	Must be within the specified tolerance range.	Based on paragraph 7.8 and paragraph 9 Measured at room temperature and standard humidity,			
Dissipation factor (tanδ)		100/(400+20C)% or less: Less than 30 pF 0.1% or less : 30 pF or larger	$ \begin{array}{ccc} 1000 \text{pF or less} & \text{Measurement frequency}: 1 \pm 0.1 \text{MHz} \\ & \text{Measurement voltage} & : 1 \pm 0.1 \text{Vrms}. \\ \text{Over } 1000 \text{pF} & \text{Measurement frequency}: 1 \pm 0.1 \text{kHz} \\ & \text{Measurement voltage} & : 1 \pm 0.1 \text{Vrms}. \\ \end{array} $			
Insulation resis	stance (IR)	10,000MΩ or 500MΩ \cdot μF, whichever is smaller	Based on paragraph 7.6 Measurement is made after rated voltage is applied for 60 \pm 5s.			
Withstanding voltage		The insulation must not be damaged.	Based on paragraph 7.1 Apply 300% of the rated voltage for 1 to 5s then measure.			
Temperature characteristics		Within $0 \pm 30 \text{ppm/}^{\circ}\text{C}$	The temperature coefficients in table 12, paragraph 7.12 are calculated at 20°C and high temperature.			
Terminal adherence		No detachment or signs of detachment.	Based on paragraph 8.11. 2. Apply 2N for 10 ± 1s in the direction indicated by the arrow. Pressure (2) Capacitor			
	Appearance	There must be no mechanical damage.	Chip is mounted to a board in the manner			
Resistance to vibration	Rate of capacitance change	Must be within initial tolerance.	shown on the right, subjected to vibration (type A in paragraph 8.2), and measured			
	Dissipation factor (tanδ)	Must satisfy initial specified value.	24 ± 2 hrs. later.			
Solderability		At least 3/4 of the surface of the two terminals must be covered with new solder.	Based on paragraph 8.13 Soldering temperature: 235 ± 5 °C Soldering time : 2 ± 0.5 s			
	Appearance	There must be no mechanical damage.	Based on paragraph 8.14. Soldering temperature: 260 ± 5°C Soldering time : 5 ± 0.5s Preheating : 150 ± 10°C for 1 to 2 min.			
ĺ	Rate of capacitance change	\pm 2.5% or \pm 0.25 pF, whichever is larger.				
Resistance to soldering	Dissipation factor (tanδ)	Must satisfy initial specified value.				
heat	Insulation resistance	10,000MΩ or 500MΩ \cdot μF, whichever is smaller				
	Withstanding voltage	The insulation must not be damaged.				
	Appearance	There must be no mechanical damage.				
Temperature cycling	Rate of capacitance change	\pm 2.5% or \pm 0.25 pF, whichever is larger.	Based on paragraph 9.3			
	Dissipation factor (tanδ)	Must satisfy initial specified value.	Number of cycles : 5			
	Insulation resistance	10,000MΩ or 500MΩ \cdot μF, whichever is smaller	Capacitance measured after 24 ± 2 hrs.			
Humidity load test	Appearance	There must be no mechanical damage.	Based on paragraph 9.9			
	Rate of capacitance change	\pm 7.5% or \pm 0.75 pF, whichever is larger.	Test temperature: 40 ± 2°C			
	Dissipation factor (tanδ)	0.5% or less	Relative humidity: 90% to 95% Applied voltage : rated voltage			
	Insulation resistance	500M Ω or 25M $\Omega \cdot \mu \text{F},$ whichever is smaller	Test time : 500 to 524 hrs. Capacitance measured after 24 ± 2 hrs.			
	Appearance	There must be no mechanical damage.	Based on paragraph 9.10			
High-	Rate of capacitance change	\pm 3.0% or \pm 0.3 pF, whichever is larger.	Test temperature: Max. operating temp.			
temperature load test	Dissipation factor (tanδ)	0.3% or less	Applied voltage : rated voltage × 200% Test time : 1,000 to 1,048 hrs.			
	Insulation resistance	1,000M Ω or 50M $\Omega \cdot \mu F$, whichever is smaller	Capacitance measured after 24 ± 2 hrs.			

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Class 2 (High dielectric constant)

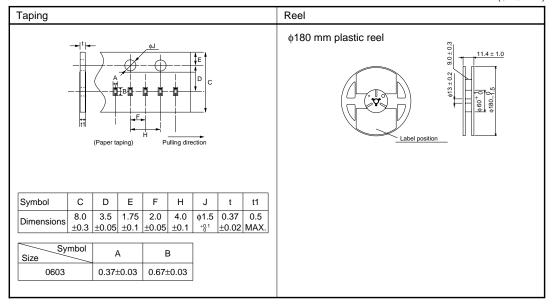
	· · · · · · · · · · · · · · · · · · ·				
Item	Temperature characteristics	CN (R) (B) (X7R)	FN (F) (Y5V)	Test methods/conditions (based on JIS C 5102)	
Operating temp	perature	−55°C ~ +125°C	-30°C ~ +85°C		
Nominal capac	citance (C)	Must be within the spe	Based on paragraph 7.8 Measured at room temperature and standard humidity, Measurement frequency: 1 ± 0.1 kHz Measurement voltage : 1.0 ± 0.2 Vrms.		
Dissipation factor	or (tanδ)	2.5% or less 5.0% or less (when rated voltage is 16V: 3.5% or less)			
Insulation resis	stance (IR)	10,000MΩ or 500MΩ · μ	Based on paragraph 7.6 Measurement is made after rated voltage is applied for 60 \pm 5s.		
Withstanding v	voltage	The insulation must not be damaged.		Based on paragraph 7.1 Apply 250% of the rated voltage for 1 to 5s then measure	
Temperature c	haracteristics	Within ± 15%	+ 22, + 82%	The temperature coefficients in paragraph 7.12, table 8, condition B, are based on measurements carried out at 20°C, with no voltage applied.	
Terminal adher	rence	No detachment or s	Based on paragraph 8. 11. 2. Apply 2N for 10 ± 1s in the direction indicated by the arrow. Pressure (2N) Capacitor Capacitor		
	Appearance	There must be no m	nechanical damage.	Chip is mounted to a board in the	
Resistance to vibration	Rate of capacitance change	Must be within	initial tolerance.	manner shown on the right, subjected to vibration (type A in paragraph 8.2),	
	Dissipation factor (tanδ)	Must satisfy initia	Il specified value.	and measured 48 ± 4 hrs. later. Board	
Solderability		At least 3/4 of the surface of the two terminals must be covered with new solder.		Based on paragraph 8. 13 Soldering temperature : 235 \pm 5°C Soldering time : 2 \pm 0.5s	
	Appearance	There must be no m			
	Rate of capacitance change	Within ± 5.0% Within ± 20.0%		Based on paragraph 8. 14.	
Resistance to soldering	Dissipation factor (tanδ)	Must satisfy initial specified value.		Soldering temperature : 260 ± 5°C Soldering time : 5 ± 0.5s Preheating : 150 ± 10°C for 1 to 2 min.	
heat	Insulation resistance	10,000M Ω or 500M $\Omega \cdot \mu F,$ whichever is smaller			
	Withstanding voltage	The insulation must not be damaged.			
	Appearance	There must be no mechanical damage.		Based on paragraph 9.3 Number of cycles : 5 Capacitance measured after 48 ± 4 hrs	
Temperature	Rate of capacitance change	Within ± 7.5% Within ± 20.0%			
cycling	Dissipation factor (tanδ)	Must satisfy initial specified value.			
	Insulation resistance	10,000M Ω or 500M Ω · μF, whichever is smaller			
	Appearance	There must be no mechanical damage.		Based on paragraph 9.9	
	Rate of capacitance change	± 12.5% or less	Within ± 30.0%	Test temperature: 40 ± 2°C	
Humidity load test			7.5% or less	Relative humidity: 90% to 95%	
test	Dissipation factor (tanδ)	5.0% or less	(when rated voltage is 16V: 10.0%)	Applied voltage : rated voltage Test time : 500 to 524 hrs.	
test	Dissipation factor (tanδ) Insulation resistance				
test	. , , ,		(when rated voltage is 16V: 10.0%) , whichever is smaller	Test time : 500 to 524 hrs.	
test	Insulation resistance	500MΩ or 25MΩ · μF	(when rated voltage is 16V: 10.0%) , whichever is smaller	Test time $:$ 500 to 524 hrs. Capacitance measured after 48 \pm 4 hrs. Based on paragraph 9.10	
High- temperature load test	Insulation resistance Appearance	500MΩ or 25MΩ · μF There must be no n	(when rated voltage is 16V: 10.0%) , whichever is smaller nechanical damage.	Test time ± 500 to 524 hrs. Capacitance measured after 48 \pm 4 hrs.	

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Packaging specifications

(Units: mm)



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• Electrical characteristics

■A (C0G) Characteristics

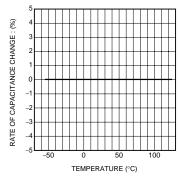


Fig.1 Capacitance-temperature characteristics

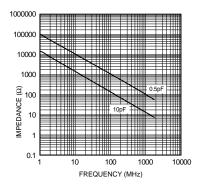


Fig.2 Impedance-frequency characteristics

■CN (X7R) Characteristics

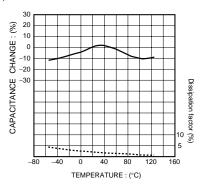


Fig.3 Capacitance-temperature characteristics

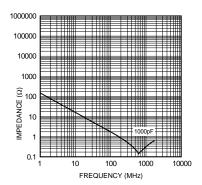


Fig.4 Impedance-frequency characteristics

■FN (Y5V) Characteristics

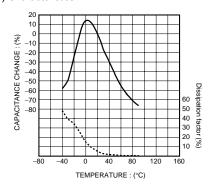


Fig.5 Capacitance-temperature characteristics

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